

DIELECTRIC CHARACTERIZATION OF CAPACITOR INSULATION

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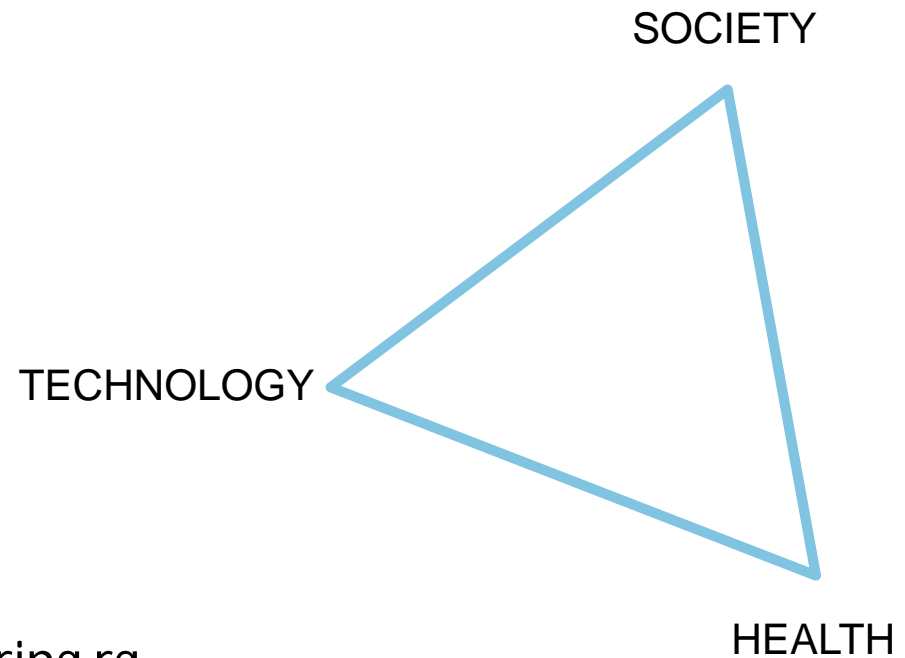
High Voltage Engineering research group



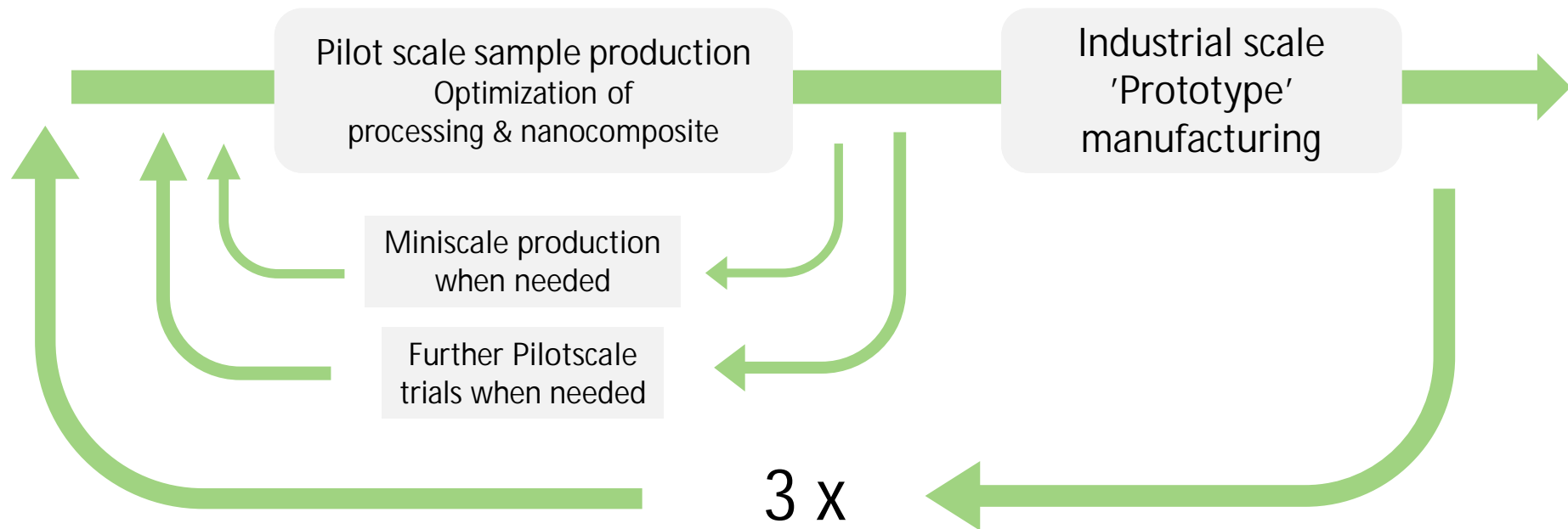
EC GRANT AGREEMENT NUMBER 720858



- Second largest university in Finland
 - ~21'000 students, ~300 professors
 - Budget ~320 M€
- Main role in the GRIDABLE project
 - Involved partner: High Voltage engineering rg
 - Dielectric characterization of capacitor thin film insulations
 - Short-term performance
 - Long-term performance, reliability
 - Leader of WP 4 "Quality and validation"



GRIDABLE approach for capacitor nanocomposite development (PP-SiO₂ BOPP film)



Dielectric characterization & material analysis after each step

Dielectric characterization of PP-SiO₂ BOPP films

- Extensive & optimized characterization
 - Development of characterization methods
- Short-term characterizations
 - 'Large area breakdown strength' distribution
 - Dielectric spectroscopy, ϵ & loss
 - Conductivity
 - Charging & trapping properties (space charge)
 - Polarization current
 - Thermally Stimulated Depolarization & Polarization currents
- Long-term characterizations
 - Electro-thermal ageing methods
 - Life testing & modelling

Optimal characterization over BOPP film development phases



+ extensive characterizations at Terichem Tervakoski and Electronicon for industrial Prototypes

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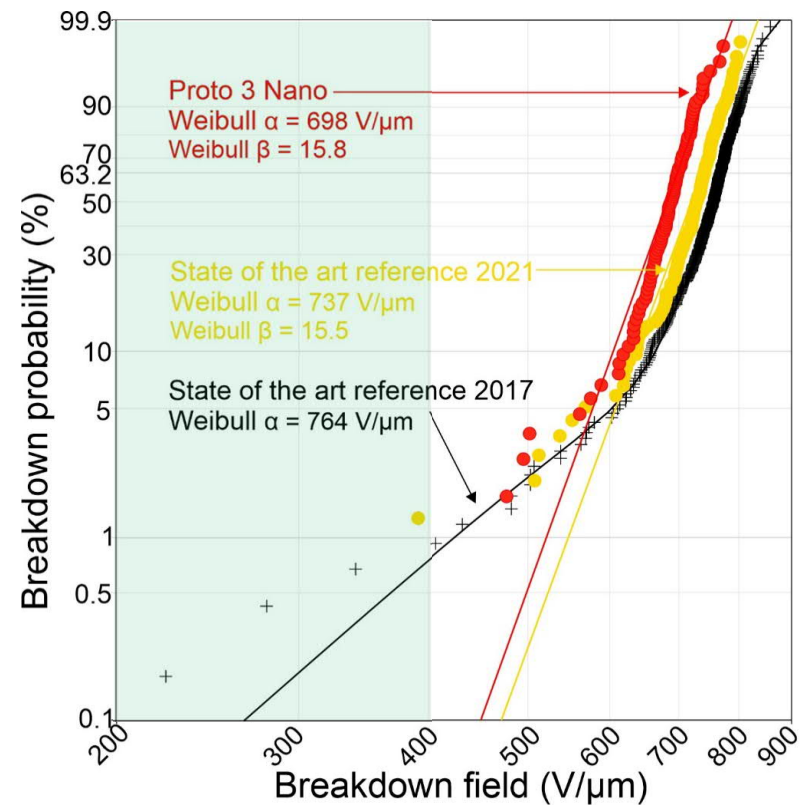
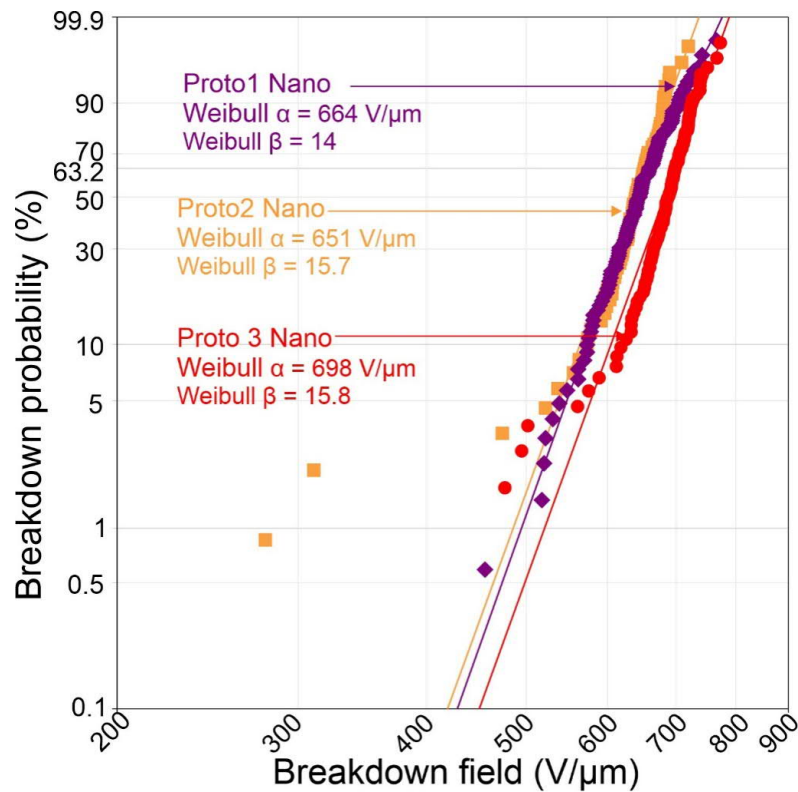
Cable insulation vs. capacitor insulation

- Bulk vs. oriented thin film (~5 – 15 μm)
- ~20 kV/mm vs. 200-250 kV/mm

→ truly critical application for a nanocomposite

+ extensive characterizations at Terichem Tervakoski and Electronicon for industrial Prototypes

PP-SiO₂ Prototypes, -breakdown strength (RT)

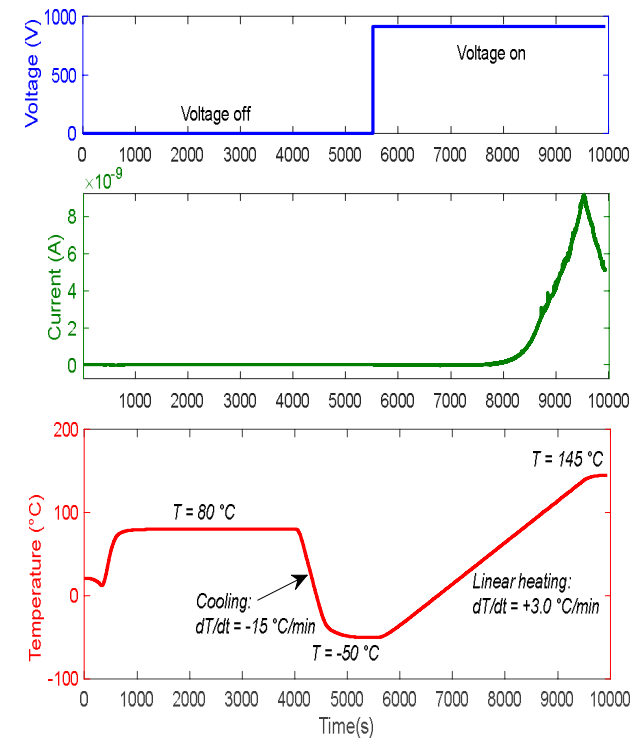
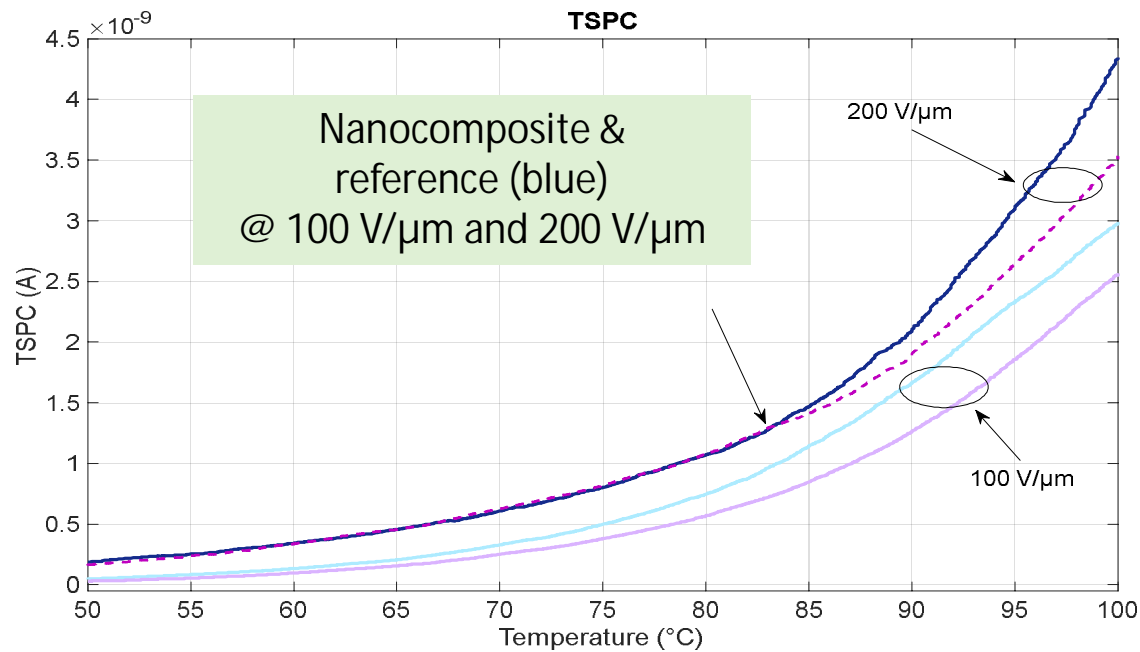


- Improved performance over the project
- Fulfils 'Specific Objective 6' of the project, -no breakdowns < 400 V/ μm



PP-SiO₂ Prototype 3, - Charging & conduction

Thermally Stimulated Polarization current



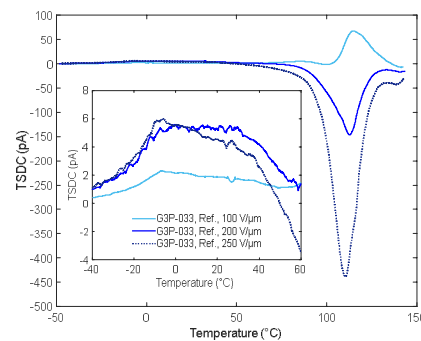
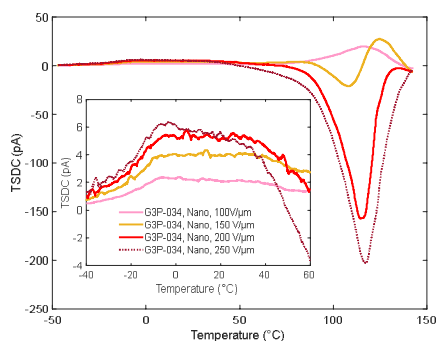
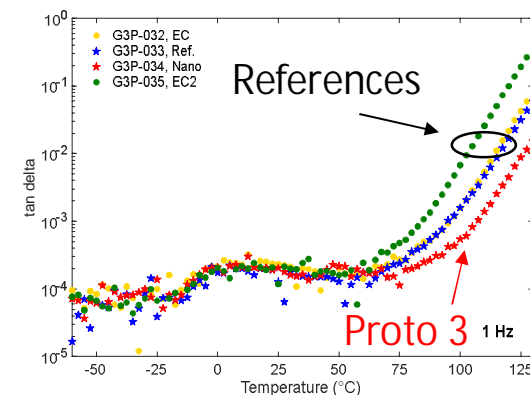
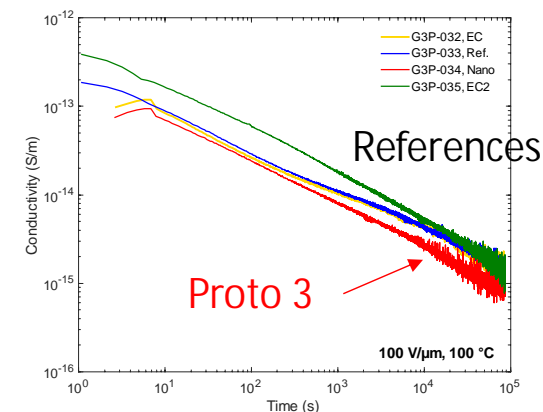
- Improved performance with nanostructuring

PP-SiO₂ Prototype 3

- conduction, dielectric loss, trap structure

Nanocomposite, compared to reference

- Lower conduction
- Lower dielectric losses at high temperatures
- Improved space charge performance
 - Lower charge injection
 - More even charge distribution



Summary & main findings

- Excellent dielectric characterization methods developed for thin films
- BOPP film, -extreme application for a nanocomposite
- Dielectric performance of the developed PP-SiO₂ nanofilm
 - **Improvements** in 'bulk' type performance evidenced (conductivity, high temperature dielectric loss, space charge)
 - **'Weak point' / 'extreme stress'** performance due to agglomeration problem
 - Limited breakdown strength
 - @ high field stresses
 - @ high temperatures
 - Limited long-term performance at high stress tests (threshold level ~200 V/μm @+60 °C)



Thank you for your attention!



This project has received funding from the European Union's Horizon 2020 research and innovation programme under grant agreement **No 720858**.

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